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SUPPLEMENTAL 1 DISCLOSURE STA	•	Docket Number 13599/1	
Application Number 10/563,662	Jul. 8, 2004	Examiner To be assigned	To be assigned
A METHOD FOR PAR CONCENTRATION M		Applicants SHAMIR et al.	

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450 I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on

Date: 8/16/06

Signature: R. Harra

- 1. In accordance with the duty of disclosure under 37 C.F.R. § 1.56 and in conformance with the procedures of 37 C.F.R. §§ 1.97 and 1.98 and M.P.E.P. § 609, attorneys for Applicants hereby bring the references listed on the attached modified PTO Form No. 1449 to the attention of the Examiner. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.
- 2. It is believed that no fees are due in connection with this Information Disclosure Statement. However, should any fees be due, the Commissioner is authorized to charge Deposit Account No. 11-0600 for such fees. A duplicate of this communication is enclosed for charging purposes.
- 3. A copy of each patent, publication or other information listed on the modified PTO form 1449 is enclosed, except as otherwise indicated.

Dated: Aug. 18, 2006

By:

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## STATEMENT BY APPLICANTS PTO-1449

Attorney Docket No. 13599/1	Serial No. 10/563,662
Applicant(s) SHAMIR et al.	
Int'l. Filing Date Jul. 8, 2004	Group Art Unit To be assigned

Jul. 8, 2004
U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT/ PUBLICATION NUMBER	PATENT/PUBLICATION DATE	NAME	CLASS	SUBCLASS	FILING DATE

## FOREIGN PATENT DOCUMENTS

EXAMINER'S	DOCUMENT					TRANS	LATION
INITIALS	NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
	WO 98/50779	Nov. 12, 1989	PCT			N/A	

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